Digitaltest preview for productronica 2011

Stutensee, Germany – September 2011 - Overwhelmingly, electronic manufacturers are seeking solutions to the end-of-line test bottlenecks that appear on high-volume product lines, where assembly beat rates are now faster than test rates. In addition, manufacturing engineering teams require techniques that can maintain test coverage and not increase the unit cost of test.

High throughput with Digitaltest MTS500 CONDOR

The MTS500 flying probe tester CONDOR captivates users with its remarkable versatility and flexibility. Apart from traditional ICT test routines, Condor is also capable of performing functional tests. Tests of prototype boards and small batches are streamlined and cost-effective.

Combining the flying prober with boundary scan, the benefits of both methods sum up to build a powerful test solution. Besides the classical in-circuit-test using four flying probes, functional tests using up to 1,012 fixed probes accessing from the bottom side are possible. These fixed probes can access the UUT using a simple magnetic probe bed or a ‘simple yet sophisticated’ vacuum operated adaptor solution. This solution is unique to THE CONDOR FLYING PROBER and offers a totally new usability for small production batches up to high volume.

Parallel testing is now possible on the MTS500 CONDOR. While the classic flying probe test runs on a certain area of the machine, another process, like functional test or memory programming can run in parallel at the same time. This offers a new dimension of throughput, test coverage and effectiveness.
Combining both flying probe and boundary scan test methods, the flying test nails CAN be used as virtual boundary scan cells to raise boundary scan test coverage. On the other hand, functional test coverage CAN be raised, as various A/D- and D/A-converter tests are possible with very little effort-

Digitaltest’s Software offerings:
C-LINK DTM provides a seamless transition from Computer Aided Design (CAD) to production, test and repair. C-LINK was introduced to the market in 1985 as the first product to link CAD, production, test and repair in a single platform.

C-LINK DTM imports CAD, schematics and Bill of Materials (BOM) data to perform Design For Test (DFT) analysis, it provides a multi-vendor solution that can support data preparation and analysis for In-Circuit Test (ICT), Flying Probe Test (FPT), Manufacturing Defects Analysis (MDA), Boundary Scan Test (BST), and Automatic Optical Inspection (AOI) systems.

The new board compare feature offers a comparison of two different layout versions and shows exactly the differences and influences for the existing fixture. This saves time and money and gives the opportunity to change the layout before it will be

released.

C-LINK QMAN is powerful yet easy to use Quality Management software. It gathers test data from the production floor to ensure product quality goals are met. It provides complete data analysis to assess the efficiency of the production proc¬ess, generate full reporting and raise alerts when problems arise.

CITE Software GenFast
„GenFast“, a new CITE module now offers test program preparation without Visual Basic. This new software module offers easy handling of test sequences in a spread sheet orientated format. The generation and debugging is now easier to handle and faster to optimize.

New Hybrid board HYB04
This new board offers „double density“ for all digital test procedures on our MTS Test system Family. NOW with 128 channels per board, up from 64, all of our testers can be upgraded to a double pin count for all hybrid (digital) pins and driver/sensors.

www.digitaltest.net [1]

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